

**Notic of References Cited**

Application/Control No.

09/653,281

Applicant(s)/Patent Under  
Reexamination:  
BEAMAN ET AL.

Examiner

Richard A. Booth

Art Unit

2812

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Ruzyllo et al., "Evaluation of Thin Oxides Grown by the Atomic Oxygen Afterglow Method", Journal of Electronic Materials, Vol. 16, No. 5, 1987, pages 373-378.
	V	
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